

# **FQB17P06 / FQI17P06**

## **60V P-Channel MOSFET**

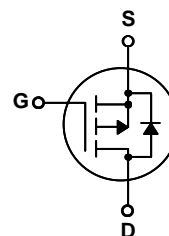
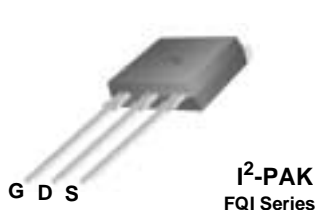
### **General Description**

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as automotive, DC/DC converters, and high efficiency switching for power management in portable and battery operated products.

### **Features**

- -17A, -60V,  $R_{DS(on)} = 0.12\Omega$  @  $V_{GS} = -10V$
- Low gate charge ( typical 21 nC)
- Low  $C_{rss}$  ( typical 80 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating
- RoHS Compliant



### **Absolute Maximum Ratings** $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FQB17P06 / FQI17P06	Units
$V_{DSS}$	Drain-Source Voltage	-60	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )	-17	A
	- Continuous ( $T_C = 100^\circ\text{C}$ )	-12	A
$I_{DM}$	Drain Current - Pulsed (Note 1)	-68	A
$V_{GSS}$	Gate-Source Voltage	$\pm 25$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	300	mJ
$I_{AR}$	Avalanche Current (Note 1)	-17	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	7.9	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	-7.0	V/ns
$P_D$	Power Dissipation ( $T_A = 25^\circ\text{C}$ ) *	3.75	W
	Power Dissipation ( $T_C = 25^\circ\text{C}$ )	79	W
	- Derate above $25^\circ\text{C}$	0.53	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +175	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

### **Thermal Characteristics**

Symbol	Parameter	Typ	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	1.9	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *	--	40	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	$^\circ\text{C/W}$

\* When mounted on the minimum pad size recommended (PCB Mount)

**Electrical Characteristics** $T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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**Off Characteristics**

$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$	-60	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = -250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	-0.06	--	V/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -60\text{ V}, V_{GS} = 0\text{ V}$	--	--	-1	$\mu\text{A}$
		$V_{DS} = -48\text{ V}, T_C = 150^\circ\text{C}$	--	--	-10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = -25\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = 25\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$	-2.0	--	-4.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = -10\text{ V}, I_D = -8.5\text{ A}$	--	0.094	0.12	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = -30\text{ V}, I_D = -8.5\text{ A}$ (Note 4)	--	9.3	--	S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = -25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	690	900	pF
$C_{oss}$	Output Capacitance		--	325	420	pF
$C_{rss}$	Reverse Transfer Capacitance		--	80	105	pF

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = -30\text{ V}, I_D = -8.5\text{ A},$ $R_G = 25\text{ }\Omega$  (Note 4, 5)	--	13	35	ns
$t_r$	Turn-On Rise Time		--	100	210	ns
$t_{d(off)}$	Turn-Off Delay Time		--	22	55	ns
$t_f$	Turn-Off Fall Time		--	60	130	ns
$Q_g$	Total Gate Charge	$V_{DS} = -48\text{ V}, I_D = -17\text{ A},$ $V_{GS} = -10\text{ V}$  (Note 4, 5)	--	21	27	nC
$Q_{gs}$	Gate-Source Charge		--	4.2	--	nC
$Q_{gd}$	Gate-Drain Charge		--	10	--	nC

**Drain-Source Diode Characteristics and Maximum Ratings**

I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current		--	--	-17	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		--	--	-68	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -17 A	--	--	-4.0	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -17 A,	--	92	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs (Note 4)	--	0.32	--	μC

**Notes:**

1. Repetitive Rating ; Pulse width limited by maximum junction temperature
2.  $L = 1.2\text{ mH}$ ,  $I_{AS} = -17\text{ A}$ ,  $V_{DD} = -25\text{ V}$ ,  $R_G = 25\text{ }\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq -17\text{ A}$ ,  $dI/dt \leq 300\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$
5. Essentially independent of operating temperature

## Typical Characteristics

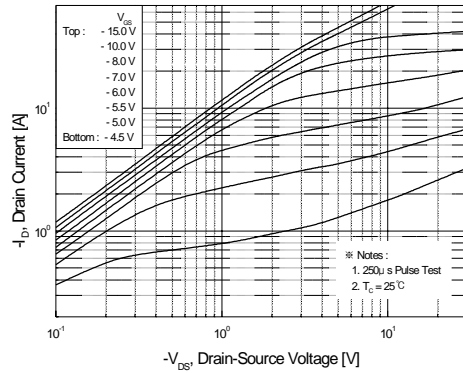


Figure 1. On-Region Characteristics

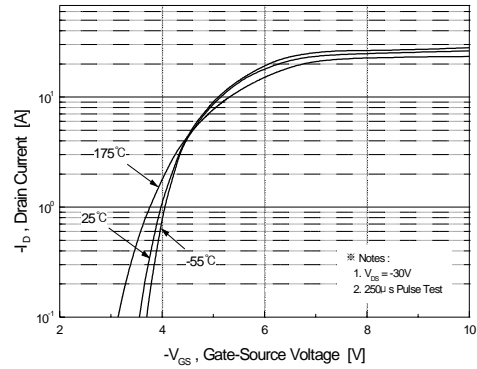


Figure 2. Transfer Characteristics

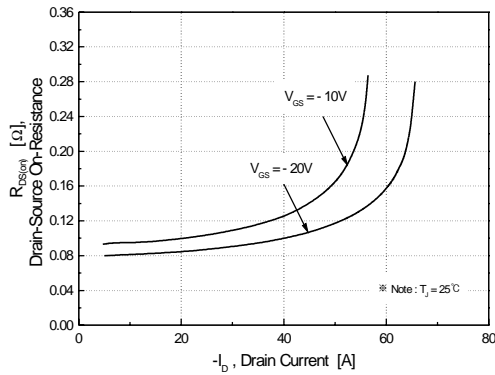


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

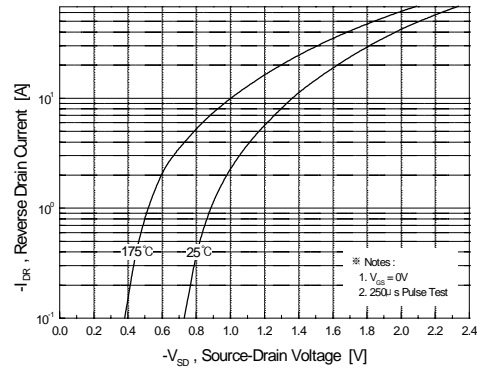


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

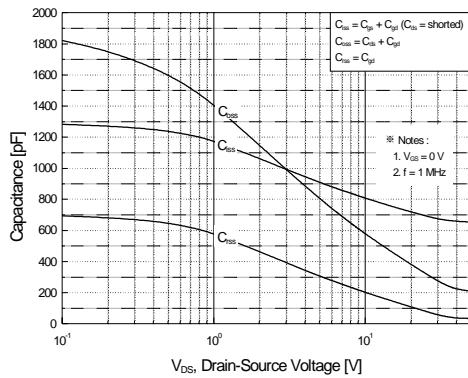


Figure 5. Capacitance Characteristics

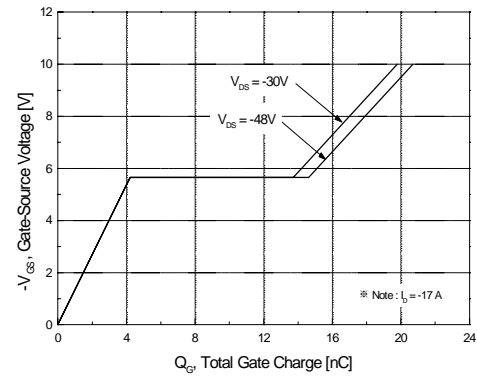
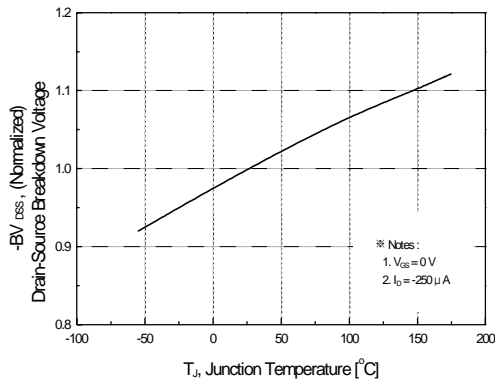
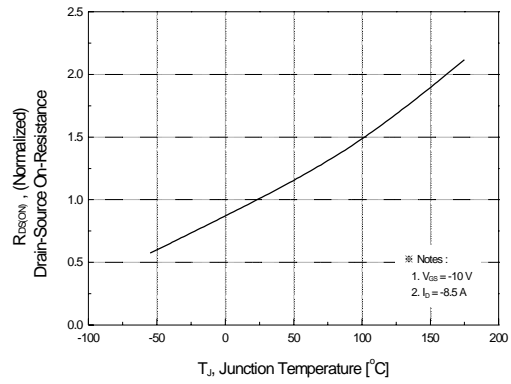


Figure 6. Gate Charge Characteristics

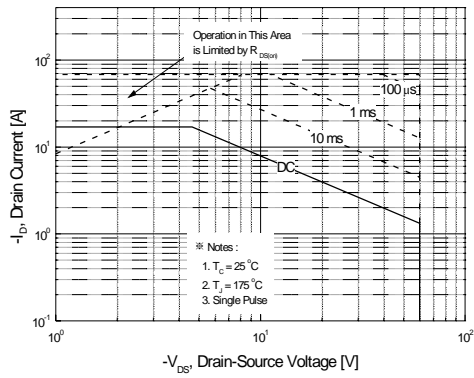
## Typical Characteristics (Continued)



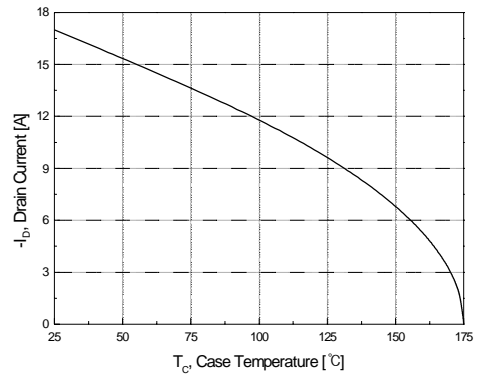
**Figure 7. Breakdown Voltage Variation vs. Temperature**



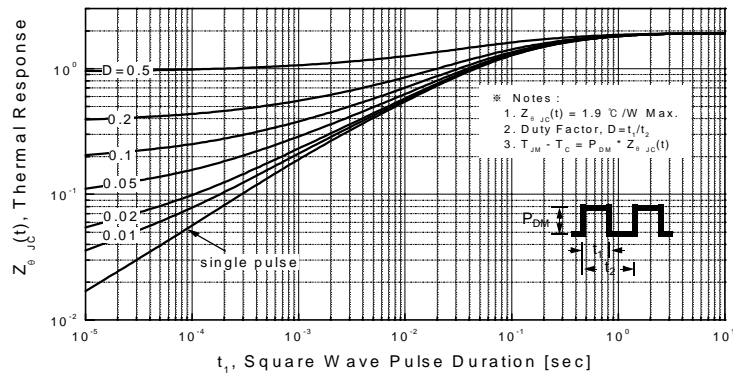
**Figure 8. On-Resistance Variation vs. Temperature**



**Figure 9. Maximum Safe Operating Area**

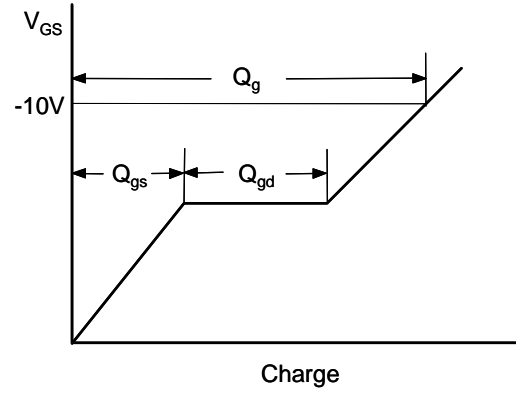
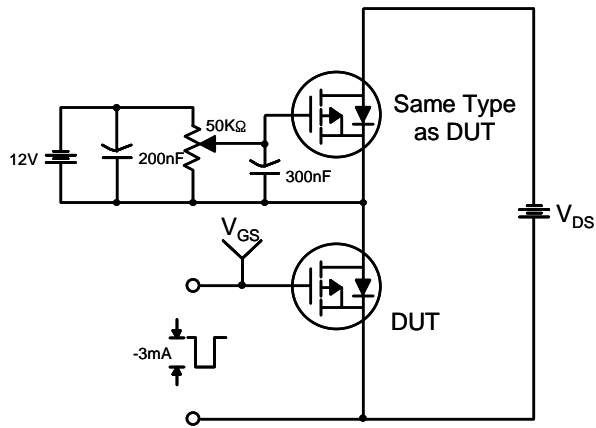


**Figure 10. Maximum Drain Current vs. Case Temperature**

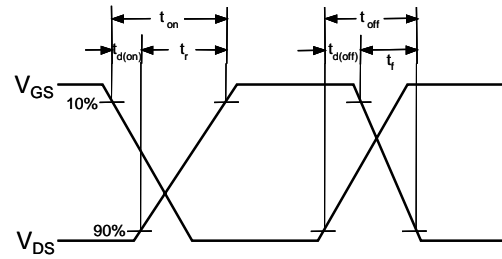
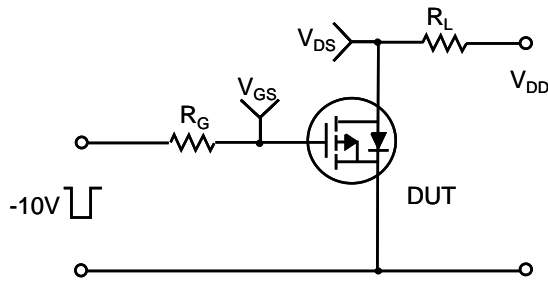


**Figure 11. Transient Thermal Response Curve**

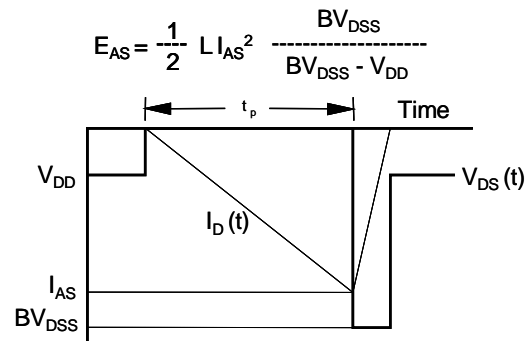
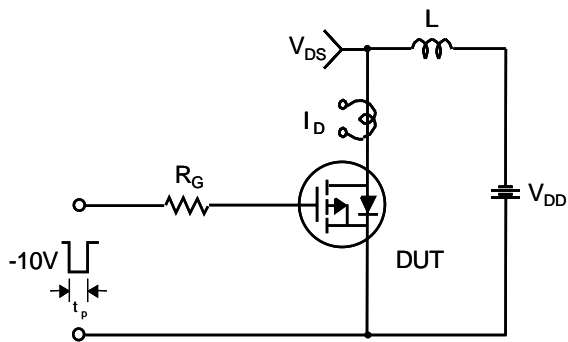
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms



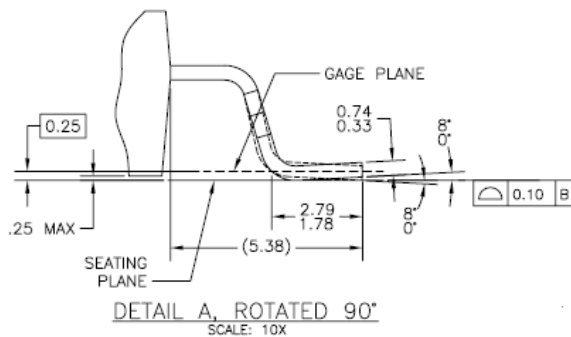
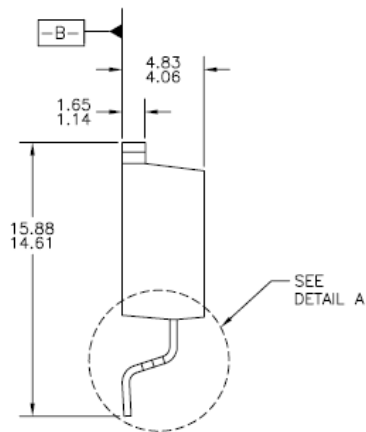
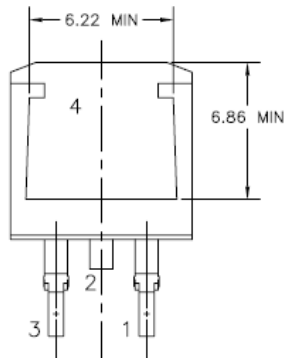
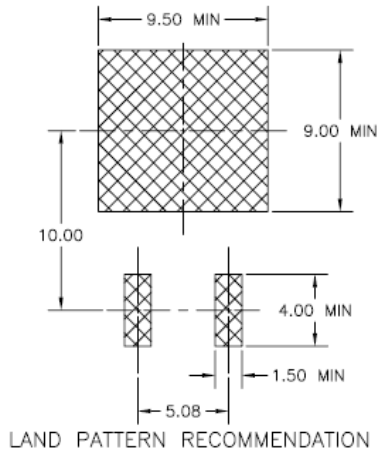
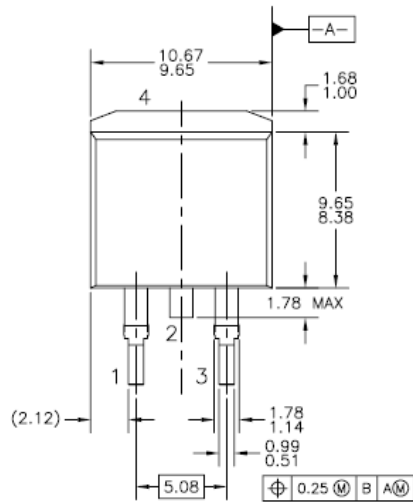
The top diagram shows a circuit for testing the body diode of a MOSFET. The MOSFET is configured with its source connected to ground and its drain connected to a load inductor  $L$  and a supply voltage  $V_{DD}$ . The gate is driven by a pulse generator  $V_{GS}$  through a gate resistor  $R_G$ . The MOSFET is labeled "Compliment of DUT (N-Channel)". The drain current is  $I_{SD}$  and the drain-source voltage is  $V_{DS}$ . The MOSFET symbol includes a circle with a diode symbol inside, labeled "DUT".

Below the circuit, three waveforms are shown:

- $V_{GS}$  (Driver):** A square wave pulse. The duty cycle is defined as  $D = \frac{\text{Gate Pulse Width}}{\text{Gate Pulse Period}}$ . The pulse height is 10V.
- $I_{SD}$  (DUT):** The drain current waveform. It shows a negative current  $I_{FM}$  (Body Diode Forward Current) during the gate pulse, followed by a reverse current  $I_{RM}$  (Body Diode Reverse Current) during the off-time. The reverse current peak is labeled  $di/dt$ .
- $V_{DS}$  (DUT):** The drain-source voltage waveform. It shows a forward voltage drop  $V_{SD}$  during the gate pulse, followed by a recovery voltage  $V_{DD}$  during the off-time. The recovery voltage is labeled "Body Diode Recovery  $dv/dt$ ".

# Mechanical Dimensions

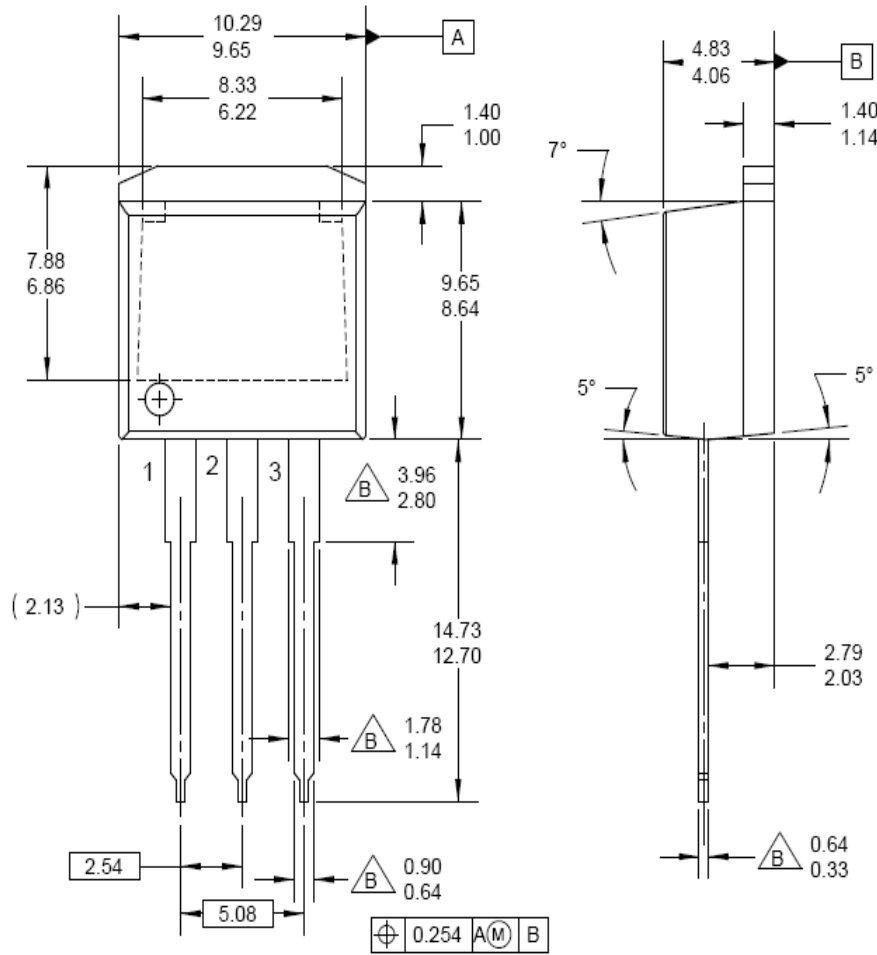
## D<sup>2</sup> - PAK



Dimensions in Millimeters

# Mechanical Dimensions

## I<sup>2</sup> - PAK



Dimensions in Millimeters





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Rev. I37